



CERTIFICATE OF ACCREDITATION

ANSI National Accreditation Board

11617 Coldwater Road, Fort Wayne, IN 46845 USA

This is to certify that

Advanced Component Testing

**3279 Veterans Memorial Hwy.
Ronkonkoma, NY 11779**

has been assessed by ANAB and meets the requirements of international standard

ISO/IEC 17025:2005

while demonstrating technical competence in the field of

TESTING

Refer to the accompanying Scope of Accreditation for information regarding the types of activities to which this accreditation applies

AT-1757

Certificate Number



ANAB Approval

Certificate Valid Through: 02/13/2021
Version No. 005 Issued: 02/05/2019



This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2005. This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory quality management system (refer to joint ISO-ILAC-IAF Communiqué dated April 2017).



ANSI National Accreditation Board

SCOPE OF ACCREDITATION TO ISO/IEC 17025:2005

Advanced Component Testing

3279 Veterans Memorial Hwy.
Ronkonkoma, NY 11779

Mike Zambito Phone: 631-676-6390
mzambito@actestlab.com www.actestlab.com

TESTING

Valid to: **February 13, 2021**

Certificate Number: **AT-1757**

Non-Destructive


Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
Resistance	MIL-STD-202G, Method 303A AS6171/7	Electrical, Electronic and Electromechanical (EEE) Components	HP 4275A
Capacitance	MIL-STD-202G, Method 305A AS6171/7	Electrical, Electronic and Electromechanical (EEE) Components	HP 4275A
Inductance	MIL-STD-202G Method 306A AS6171/7	Electrical, Electronic and Electromechanical (EEE) Components	HP 4275A
Group A Electrical	MIL-STD-883 AS6171/7	Electrical, Electronic and Electromechanical (EEE) Components	ATE and various Electronic Lab Equipment Temperature Chamber
Elemental Content by XRF	Internal Procedure AS6081 AS6171/3	Electrical, Electronic and Electromechanical (EEE) Components	Niton XL3t / test slug
Radiographic Examination / Inspection	Internal Procedure AS6081 AS6171/5	Electrical, Electronic and Electromechanical (EEE) Components	Glenbrook Jewel Box 70T
Visual Inspection	Internal Procedure IDEA-STD-1010B AS6081 AS6171/2	Electrical, Electronic and Electromechanical (EEE) Components	Dino-Lite Camera
Marking Permanency Test	MIL-STD-202G, Method 215K Internal Procedure AS6081 AS6171/2	Electrical, Electronic and Electromechanical (EEE) Components	Chemical Solution

Non-Destructive

Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
Packaging Configuration and Dimensions	MIL-STD-883 Method 2016 Internal Procedure AS6081 AS6171/2 Excluding Part Weight Measurement	Electrical, Electronic and Electromechanical (EEE) Components	Calipers Device to print Package Dimensions
Solderability	MIL-STD-883 Method 2003.9 Internal Procedure	Electrical, Electronic and Electromechanical (EEE) Components	RPS Steam Ager Solder Pots Digital Thermometer
Testing for Resurfacing	IDEA-STD-1010B AS6081 AS6171/2	Electrical, Electronic and Electromechanical (EEE) Components	Mark-Scrape test Chemical Solutions Dynasolve Digital Thermometer
Decapsulation and Die Verification	IDEA-STD-1010B Internal Procedure AS6081 AS6171/4	Electrical, Electronic and Electromechanical (EEE) Components	Nisene Jet-Etch Decapsulator, Microscope
SEM	AS 6081 AS 6171/2 Internal Procedure	Electrical, Electronic and Electromechanical (EEE) Components	SEM Scanning Electron Microscope

Note:

1. This scope is formatted as part of a single document including Certificate of Accreditation No. AT-1757.



Vice President

